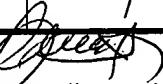


Issue Classification				Application/Control No.	Applicant(s)/Patent under Reexamination	
				09/533,148	LIN, EDDIE HUEY CHIUN	
				Examiner	Art Unit	
				Yasin M. Barqadle	2153	

ORIGINAL				CROSS REFERENCE(S)				
CLASS		SUBCLASS		CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)			
709		238		709	239	245		
INTERNATIONAL CLASSIFICATION				370	395.31			
G	0	6	F	15/173				
H	0	4	L	12/56				
				/				
				/				
				/				
 Yasin Barqadle (Assistant Examiner)				 Dung C. Dinh Primary Examiner 11/16/05 (Primary Examiner)			Total Claims Allowed: 22	
 Sharon Cutton (Legal Instruments Examiner)				 11/16/05 (Date)			O.G. Print Claim(s) 1	O.G. Print Fig. 9A

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
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